

# IS41C8512 IS41LV8512



## 512K x 8 (4-MBIT) DYNAMIC RAM WITH EDO PAGE MODE

### FEATURES

- Extended Data-Out (EDO) Page Mode access cycle
- TTL compatible inputs and outputs; tristate I/O
- Refresh Interval: 1024 cycles /16 ms
- Refresh Mode:  $\overline{\text{RAS}}$ -Only,  $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$  (CBR), Hidden
- JEDEC standard pinout
- Single power supply:
  - 5V  $\pm$  10% (IS41C8512)
  - 3.3V  $\pm$  10% (IS41LV8512)
- Byte Write and Byte Read operation via  $\overline{\text{CAS}}$
- Industrial Temperature Range -40°C to 85°C

### DESCRIPTION

The *ICSI* IS41C8512 and IS41LV8512 is a 524,288 x 8-bit high-performance CMOS Dynamic Random Access Memories. The IS41C8512 offer an accelerated cycle access called EDO Page Mode. EDO Page Mode allows 512 random accesses within a single row with access cycle time as short as 10 ns per 8-bit.

These features make the IS41C8512 and IS41LV8512 ideally suited for high-bandwidth graphics, digital signal processing, high-performance computing systems, and peripheral applications.

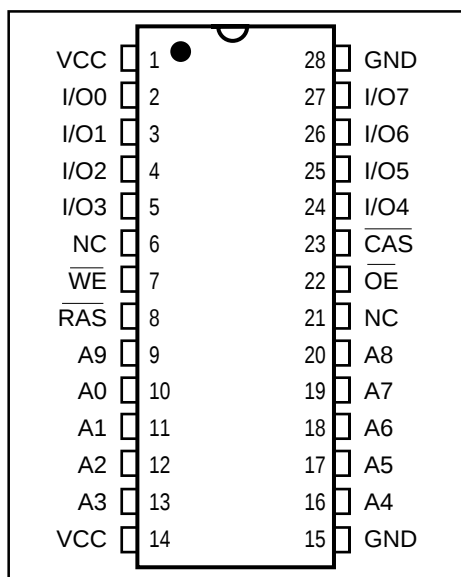
The IS41C8512 is packaged in a 28-pin 400mil SOJ and 400mil TSOP-2.

### KEY TIMING PARAMETERS

| Parameter                                                     | -35 | -50 | -60 | Unit |
|---------------------------------------------------------------|-----|-----|-----|------|
| Max. $\overline{\text{RAS}}$ Access Time ( $t_{\text{RAC}}$ ) | 35  | 50  | 60  | ns   |
| Max. $\overline{\text{CAS}}$ Access Time ( $t_{\text{CAC}}$ ) | 10  | 14  | 15  | ns   |
| Max. Column Address Access Time ( $t_{\text{AA}}$ )           | 18  | 25  | 30  | ns   |
| Min. EDO Page Mode Cycle Time ( $t_{\text{PC}}$ )             | 12  | 20  | 25  | ns   |
| Min. Read/Write Cycle Time ( $t_{\text{RC}}$ )                | 60  | 90  | 110 | ns   |

### PIN CONFIGURATIONS

28 Pin SOJ, TSOP-2

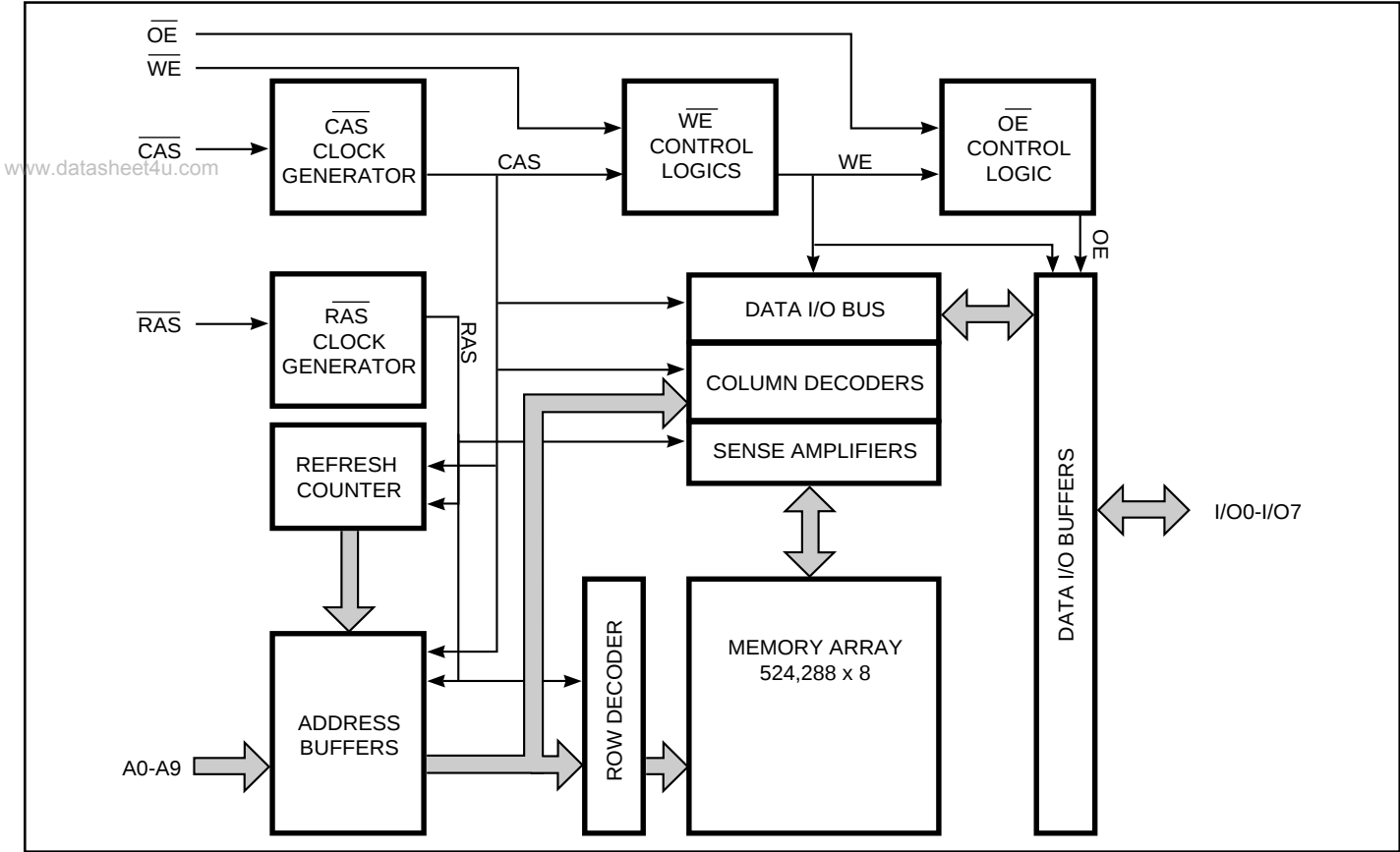


### PIN DESCRIPTIONS

|                         |                       |
|-------------------------|-----------------------|
| A0-A9                   | Address Inputs        |
| I/O0-7                  | Data Inputs/Outputs   |
| $\overline{\text{WE}}$  | Write Enable          |
| $\overline{\text{OE}}$  | Output Enable         |
| $\overline{\text{RAS}}$ | Row Address Strobe    |
| $\overline{\text{CAS}}$ | Column Address Strobe |
| Vcc                     | Power                 |
| GND                     | Ground                |
| NC                      | No Connection         |

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FUNCTIONAL BLOCK DIAGRAM



TRUTH TABLE

| Function                       |                      | $\overline{RAS}$ | $\overline{CAS}$ | $\overline{WE}$ | $\overline{OE}$ | Address $t_R/t_C$ | I/O                                |
|--------------------------------|----------------------|------------------|------------------|-----------------|-----------------|-------------------|------------------------------------|
| Standby                        |                      | H                | H                | X               | X               | X                 | High-Z                             |
| Read                           |                      | L                | L                | H               | L               | ROW/COL           | D <sub>OUT</sub>                   |
| Write: Word (Early Write)      |                      | L                | L                | L               | X               | ROW/COL           | D <sub>IN</sub>                    |
| Read-Write                     |                      | L                | L                | H→L             | L→H             | ROW/COL           | D <sub>OUT</sub> , D <sub>IN</sub> |
| Hidden Refresh                 | Read                 | L→H→L            | L                | H               | L               | ROW/COL           | D <sub>OUT</sub>                   |
|                                | Write <sup>(1)</sup> | L→H→L            | L                | L               | X               | ROW/COL           | D <sub>OUT</sub>                   |
| $\overline{RAS}$ -Only Refresh |                      | L                | H                | X               | X               | ROW/NA            | High-Z                             |
| CBR Refresh                    |                      | H→L              | L                | X               | X               | X                 | High-Z                             |

Note:  
1. EARLY WRITE only.

## Functional Description

The IS41C8512 and IS41LV8512 is a CMOS DRAM optimized for high-speed bandwidth, low power applications. During READ or WRITE cycles, each bit is uniquely addressed through the 10 address bits. These are entered ten bits (A0-A9) at a time. The row address is latched by the Row Address Strobe ( $\overline{\text{RAS}}$ ). The column address is latched by the Column Address Strobe ( $\overline{\text{CAS}}$ ).  $\overline{\text{RAS}}$  is used to latch the first ten bits and  $\overline{\text{CAS}}$  is used the latter nine bits.

## Memory Cycle

A memory cycle is initiated by bring  $\overline{\text{RAS}}$  LOW and it is terminated by returning both  $\overline{\text{RAS}}$  and  $\overline{\text{CAS}}$  HIGH. To ensures proper device operation and data integrity any memory cycle, once initiated, must not be ended or aborted before the minimum  $t_{\text{RAS}}$  time has expired. A new cycle must not be initiated until the minimum precharge time  $t_{\text{RP}}$ ,  $t_{\text{CP}}$  has elapsed.

## Read Cycle

A read cycle is initiated by the falling edge of  $\overline{\text{CAS}}$  or  $\overline{\text{OE}}$ , whichever occurs last, while holding  $\overline{\text{WE}}$  HIGH. The column address must be held for a minimum time specified by  $t_{\text{AR}}$ . Data Out becomes valid only when  $t_{\text{RAC}}$ ,  $t_{\text{AA}}$ ,  $t_{\text{CAC}}$  and  $t_{\text{OEA}}$  are all satisfied. As a result, the access time is dependent on the timing relationships between these parameters.

## Write Cycle

A write cycle is initiated by the falling edge of  $\overline{\text{CAS}}$  and  $\overline{\text{WE}}$ , whichever occurs last. The input data must be valid at or before the falling edge of  $\overline{\text{CAS}}$  or  $\overline{\text{WE}}$ , whichever occurs first.

## Refresh Cycle

To retain data, 1024 refresh cycles are required in each 16 ms period. There are two ways to refresh the memory.

1. By clocking each of the 1024 row addresses (A0 through A9) with  $\overline{\text{RAS}}$  at least once every 16 ms. Any read, write, read-modify-write or  $\overline{\text{RAS}}$ -only cycle refreshes the addressed row.
2. Using a  $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$  refresh cycle.  $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$  refresh is activated by the falling edge of  $\overline{\text{RAS}}$ , while holding  $\overline{\text{CAS}}$  LOW. In  $\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$  refresh cycle, an internal 10-bit counter provides the row addresses and the external address inputs are ignored.

$\overline{\text{CAS}}$ -before- $\overline{\text{RAS}}$  is a refresh-only mode and no data access or device selection is allowed. Thus, the output remains in the High-Z state during the cycle.

## Extended Data Out Page Mode

EDO page mode operation permits all 512 columns within a selected row to be randomly accessed at a high data rate.

In EDO page mode read cycle, the data-out is held to the next  $\overline{\text{CAS}}$  cycle's falling edge, instead of the rising edge. For this reason, the valid data output time in EDO page mode is extended compared with the fast page mode. In the fast page mode, the valid data output time becomes shorter as the  $\overline{\text{CAS}}$  cycle time becomes shorter. Therefore, in EDO page mode, the timing margin in read cycle is larger than that of the fast page mode even if the  $\overline{\text{CAS}}$  cycle time becomes shorter.

In EDO page mode, due to the extended data function, the  $\overline{\text{CAS}}$  cycle time can be shorter than in the fast page mode if the timing margin is the same.

The EDO page mode allows both read and write operations during one  $\overline{\text{RAS}}$  cycle, but the performance is equivalent to that of the fast page mode in that case.

## Power-On

After application of the  $V_{\text{CC}}$  supply, an initial pause of 200  $\mu\text{s}$  is required followed by a minimum of eight initialization cycles (any combination of cycles containing a  $\overline{\text{RAS}}$  signal).

During power-on, it is recommended that  $\overline{\text{RAS}}$  track with  $V_{\text{CC}}$  or be held at a valid  $V_{\text{IH}}$  to avoid current surges.

ABSOLUTE MAXIMUM RATINGS<sup>(1)</sup>

| Symbol           | Parameters                         |      | Rating       | Unit |
|------------------|------------------------------------|------|--------------|------|
| V <sub>T</sub>   | Voltage on Any Pin Relative to GND | 5V   | −1.0 to +7.0 | V    |
|                  |                                    | 3.3V | −0.5 to +4.6 |      |
| V <sub>CC</sub>  | Supply Voltage                     | 5V   | −1.0 to +7.0 | V    |
|                  |                                    | 3.3V | −0.5 to +4.6 |      |
| I <sub>OUT</sub> | Output Current                     |      | 50           | mA   |
| P <sub>D</sub>   | Power Dissipation                  |      | 1            | W    |
| T <sub>A</sub>   | Commercial Operation Temperature   |      | 0 to +70     | °C   |
|                  | Industrial Operating Temperature   |      | −40 to +85   | °C   |
| T <sub>STG</sub> | Storage Temperature                |      | −55 to +125  | °C   |

Note:

1. Stress greater than those listed under ABSOLUTE MAXIMUM RATINGS may cause permanent damage to the device. This is a stress rating only and functional operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied. Exposure to absolute maximum rating conditions for extended periods may affect reliability.

## RECOMMENDED OPERATING CONDITIONS (Voltages are referenced to GND.)

| Symbol          | Parameter                      |      | Min. | Typ. | Max.                  | Unit |
|-----------------|--------------------------------|------|------|------|-----------------------|------|
| V <sub>CC</sub> | Supply Voltage                 | 5V   | 4.5  | 5.0  | 5.5                   | V    |
|                 |                                | 3.3V | 3.0  | 3.3  | 3.6                   |      |
| V <sub>IH</sub> | Input High Voltage             | 5V   | 2.4  | —    | V <sub>CC</sub> + 1.0 | V    |
|                 |                                | 3.3V | 2.0  | —    | V <sub>CC</sub> + 0.3 |      |
| V <sub>IL</sub> | Input Low Voltage              | 5V   | −1.0 | —    | 0.8                   | V    |
|                 |                                | 3.3V | −0.3 | —    | 0.8                   |      |
| T <sub>A</sub>  | Commercial Ambient Temperature |      | 0    | —    | 70                    | °C   |
|                 | Industrial Ambient Temperature |      | −40  | —    | 85                    | °C   |

CAPACITANCE<sup>(1,2)</sup>

| Symbol           | Parameter                                                                                                                                          | Max. | Unit |
|------------------|----------------------------------------------------------------------------------------------------------------------------------------------------|------|------|
| C <sub>IN1</sub> | Input Capacitance: A0-A8                                                                                                                           | 5    | pF   |
| C <sub>IN2</sub> | Input Capacitance: $\overline{\text{RAS}}$ , $\overline{\text{UCAS}}$ , $\overline{\text{LCAS}}$ , $\overline{\text{WE}}$ , $\overline{\text{OE}}$ | 7    | pF   |
| C <sub>IO</sub>  | Data Input/Output Capacitance: I/O0-I/O15                                                                                                          | 7    | pF   |

Notes:

1. Tested initially and after any design or process changes that may affect these parameters.
2. Test conditions: T<sub>A</sub> = 25°C, f = 1 MHz.

## ELECTRICAL CHARACTERISTICS<sup>(1)</sup>

(Recommended Operating Conditions unless otherwise noted.)

| Symbol           | Parameter                                                                                   | Test Condition                                                                                     | Speed                                                            | Min.             | Max.              | Unit    |
|------------------|---------------------------------------------------------------------------------------------|----------------------------------------------------------------------------------------------------|------------------------------------------------------------------|------------------|-------------------|---------|
| I <sub>IL</sub>  | Input Leakage Current                                                                       | Any input $0V \leq V_{IN} \leq V_{CC}$<br>Other inputs not under test = 0V                         |                                                                  | -10              | 10                | $\mu A$ |
| I <sub>IO</sub>  | Output Leakage Current                                                                      | Output is disabled (Hi-Z)<br>$0V \leq V_{OUT} \leq V_{CC}$                                         |                                                                  | -10              | 10                | $\mu A$ |
| V <sub>OH</sub>  | Output High Voltage Level                                                                   | I <sub>OH</sub> = -2.5 mA                                                                          |                                                                  | 2.4              | —                 | V       |
| V <sub>OL</sub>  | Output Low Voltage Level                                                                    | I <sub>OL</sub> = +2.1 mA                                                                          |                                                                  | —                | 0.4               | V       |
| I <sub>CC1</sub> | Standby Current: TTL                                                                        | $\overline{RAS}, \overline{CAS} \geq V_{IH}$                                                       | Commerical 5V<br>Industrial 5V<br>Commerical 3V<br>Industrial 3V | —<br>—<br>—<br>— | 3<br>4<br>2<br>3  | mA      |
| I <sub>CC2</sub> | Standby Current: CMOS                                                                       | $\overline{RAS}, \overline{CAS} \geq V_{CC} - 0.2V$                                                | 5V<br>3V                                                         | —<br>—           | 2<br>1            | mA      |
| I <sub>CC3</sub> | Operating Current:<br>Random Read/Write <sup>(2,3,4)</sup><br>Average Power Supply Current  | $\overline{RAS}, \overline{CAS}$ ,<br>Address Cycling, t <sub>RC</sub> = t <sub>RC</sub> (min.)    | -35<br>-50<br>-60                                                | —<br>—<br>—      | 230<br>180<br>170 | mA      |
| I <sub>CC4</sub> | Operating Current:<br>EDO Page Mode <sup>(2,3,4)</sup><br>Average Power Supply Current      | $\overline{RAS} = V_{IL}, \overline{CAS}$ ,<br>Cycling t <sub>PC</sub> = t <sub>PC</sub> (min.)    | -35<br>-50<br>-60                                                | —<br>—<br>—      | 220<br>170<br>160 | mA      |
| I <sub>CC5</sub> | Refresh Current:<br>$\overline{RAS}$ -Only <sup>(2,3)</sup><br>Average Power Supply Current | $\overline{RAS}$ Cycling, $\overline{CAS} \geq V_{IH}$<br>t <sub>RC</sub> = t <sub>RC</sub> (min.) | -35<br>-50<br>-60                                                | —<br>—<br>—      | 230<br>180<br>170 | mA      |
| I <sub>CC6</sub> | Refresh Current:<br>CBR <sup>(2,3,5)</sup><br>Average Power Supply Current                  | $\overline{RAS}, \overline{CAS}$ Cycling<br>t <sub>RC</sub> = t <sub>RC</sub> (min.)               | -35<br>-50<br>-60                                                | —<br>—<br>—      | 230<br>180<br>170 | mA      |

### Notes:

1. An initial pause of 200  $\mu s$  is required after power-up followed by eight  $\overline{RAS}$  refresh cycles ( $\overline{RAS}$ -Only or CBR) before proper device operation is assured. The eight  $\overline{RAS}$  cycles wake-up should be repeated any time the t<sub>REF</sub> refresh requirement is exceeded.
2. Dependent on cycle rates.
3. Specified values are obtained with minimum cycle time and the output open.
4. Column-address is changed once each EDO page cycle.
5. Enables on-chip refresh and address counters.

AC CHARACTERISTICS<sup>(1,2,3,4,5,6)</sup>

(Recommended Operating Conditions unless otherwise noted.)

| Symbol            | Parameter                                                                                  | -35  |      | -50  |      | -60  |      | Units |
|-------------------|--------------------------------------------------------------------------------------------|------|------|------|------|------|------|-------|
|                   |                                                                                            | Min. | Max. | Min. | Max. | Min. | Max. |       |
| t <sub>RC</sub>   | Random READ or WRITE Cycle Time                                                            | 60   | —    | 90   | —    | 110  | —    | ns    |
| t <sub>RAC</sub>  | Access Time from $\overline{\text{RAS}}$ <sup>(6, 7)</sup>                                 | 35   | —    | 50   | —    | —    | 60   | ns    |
| t <sub>CAC</sub>  | Access Time from $\overline{\text{CAS}}$ <sup>(6, 8, 15)</sup>                             | —    | 10   | —    | 14   | —    | 15   | ns    |
| t <sub>AA</sub>   | Access Time from Column-Address <sup>(6)</sup>                                             | —    | 18   | —    | 25   | —    | 30   | ns    |
| t <sub>RAS</sub>  | $\overline{\text{RAS}}$ Pulse Width                                                        | 35   | 10K  | 50   | 10K  | 60   | 10K  | ns    |
| t <sub>RP</sub>   | $\overline{\text{RAS}}$ Precharge Time                                                     | 20   | —    | 30   | —    | 40   | —    | ns    |
| t <sub>CAS</sub>  | $\overline{\text{CAS}}$ Pulse Width <sup>(26)</sup>                                        | 6    | 10K  | 8    | 10K  | 10   | 10K  | ns    |
| t <sub>CP</sub>   | $\overline{\text{CAS}}$ Precharge Time <sup>(9, 25)</sup>                                  | 5    | —    | 8    | —    | 10   | —    | ns    |
| t <sub>CSH</sub>  | $\overline{\text{CAS}}$ Hold Time <sup>(21)</sup>                                          | 35   | —    | 50   | —    | 60   | —    | ns    |
| t <sub>RCD</sub>  | $\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Delay Time <sup>(10, 20)</sup>          | 11   | 28   | 19   | 36   | 20   | 45   | ns    |
| t <sub>ASR</sub>  | Row-Address Setup Time                                                                     | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>RAH</sub>  | Row-Address Hold Time                                                                      | 6    | —    | 8    | —    | 10   | —    | ns    |
| t <sub>ASC</sub>  | Column-Address Setup Time <sup>(20)</sup>                                                  | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>CAH</sub>  | Column-Address Hold Time <sup>(20)</sup>                                                   | 6    | —    | 8    | —    | 10   | —    | ns    |
| t <sub>AR</sub>   | Column-Address Hold Time<br>(referenced to $\overline{\text{RAS}}$ )                       | 30   | —    | 40   | —    | 40   | —    | ns    |
| t <sub>RAD</sub>  | $\overline{\text{RAS}}$ to Column-Address Delay Time <sup>(11)</sup>                       | 10   | 20   | 14   | 25   | 15   | 30   | ns    |
| t <sub>RAL</sub>  | Column-Address to $\overline{\text{RAS}}$ Lead Time                                        | 18   | —    | 25   | —    | 30   | —    | ns    |
| t <sub>RPC</sub>  | $\overline{\text{RAS}}$ to $\overline{\text{CAS}}$ Precharge Time                          | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>RSH</sub>  | $\overline{\text{RAS}}$ Hold Time <sup>(27)</sup>                                          | 8    | —    | 14   | —    | 15   | —    | ns    |
| t <sub>CLZ</sub>  | $\overline{\text{CAS}}$ to Output in Low-Z <sup>(15, 29)</sup>                             | 3    | —    | 3    | —    | 3    | —    | ns    |
| t <sub>CRP</sub>  | $\overline{\text{CAS}}$ to $\overline{\text{RAS}}$ Precharge Time <sup>(21)</sup>          | 5    | —    | 5    | —    | 5    | —    | ns    |
| t <sub>OD</sub>   | Output Disable Time <sup>(19, 28, 29)</sup>                                                | 3    | 12   | 3    | 12   | 3    | 12   | ns    |
| t <sub>OE</sub>   | Output Enable Time <sup>(15, 16)</sup>                                                     | 0    | 10   | 0    | 15   | —    | 15   | ns    |
| t <sub>OEHC</sub> | $\overline{\text{OE}}$ HIGH Hold Time from $\overline{\text{CAS}}$ HIGH                    | 10   | —    | 10   | —    | 10   | —    | ns    |
| t <sub>OE P</sub> | $\overline{\text{OE}}$ HIGH Pulse Width                                                    | 10   | —    | 10   | —    | 10   | —    | ns    |
| t <sub>OES</sub>  | $\overline{\text{OE}}$ LOW to $\overline{\text{CAS}}$ HIGH Setup Time                      | 5    | —    | 5    | —    | 5    | —    | ns    |
| t <sub>RCS</sub>  | Read Command Setup Time <sup>(17, 20)</sup>                                                | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>RRH</sub>  | Read Command Hold Time<br>(referenced to $\overline{\text{RAS}}$ ) <sup>(12)</sup>         | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>RCH</sub>  | Read Command Hold Time<br>(referenced to $\overline{\text{CAS}}$ ) <sup>(12, 17, 21)</sup> | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>WCH</sub>  | Write Command Hold Time <sup>(17, 27)</sup>                                                | 5    | —    | 8    | —    | 10   | —    | ns    |
| t <sub>WCR</sub>  | Write Command Hold Time<br>(referenced to $\overline{\text{RAS}}$ ) <sup>(17)</sup>        | 30   | —    | 40   | —    | 50   | —    | ns    |
| t <sub>WP</sub>   | Write Command Pulse Width <sup>(17)</sup>                                                  | 5    | —    | 8    | —    | 10   | —    | ns    |
| t <sub>WPZ</sub>  | $\overline{\text{WE}}$ Pulse Widths to Disable Outputs                                     | 10   | —    | 10   | —    | 10   | —    | ns    |
| t <sub>RWL</sub>  | Write Command to $\overline{\text{RAS}}$ Lead Time <sup>(17)</sup>                         | 8    | —    | 14   | —    | 15   | —    | ns    |
| t <sub>CWL</sub>  | Write Command to $\overline{\text{CAS}}$ Lead Time <sup>(17, 21)</sup>                     | 8    | —    | 14   | —    | 15   | —    | ns    |
| t <sub>WCS</sub>  | Write Command Setup Time <sup>(14, 17, 20)</sup>                                           | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>DHR</sub>  | Data-in Hold Time (referenced to $\overline{\text{RAS}}$ )                                 | 30   | —    | 40   | —    | 40   | —    | ns    |

AC CHARACTERISTICS (Continued)<sup>(1,2,3,4,5,6)</sup>

(Recommended Operating Conditions unless otherwise noted.)

| Symbol            | Parameter                                                                                                      | -35  |      | -50  |      | -60  |      | Units |
|-------------------|----------------------------------------------------------------------------------------------------------------|------|------|------|------|------|------|-------|
|                   |                                                                                                                | Min. | Max. | Min. | Max. | Min. | Max. |       |
| t <sub>ACH</sub>  | Column-Address Setup Time to $\overline{\text{CAS}}$ Precharge during WRITE Cycle                              | 15   | —    | 15   | —    | 15   | —    | ns    |
| t <sub>OE</sub>   | $\overline{\text{OE}}$ Hold Time from $\overline{\text{WE}}$ during READ-MODIFY-WRITE cycle <sup>(18)</sup>    | 8    | —    | 8    | —    | 15   | —    | ns    |
| t <sub>DS</sub>   | Data-In Setup Time <sup>(15, 22)</sup>                                                                         | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>DH</sub>   | Data-In Hold Time <sup>(15, 22)</sup>                                                                          | 6    | —    | 6    | —    | 10   | —    | ns    |
| t <sub>RWC</sub>  | READ-MODIFY-WRITE Cycle Time                                                                                   | 80   | —    | 100  | —    | 140  | —    | ns    |
| t <sub>RWD</sub>  | $\overline{\text{RAS}}$ to $\overline{\text{WE}}$ Delay Time during READ-MODIFY-WRITE Cycle <sup>(14)</sup>    | 45   | —    | 50   | —    | 80   | —    | ns    |
| t <sub>CWD</sub>  | $\overline{\text{CAS}}$ to $\overline{\text{WE}}$ Delay Time <sup>(14, 20)</sup>                               | 25   | —    | 30   | —    | 36   | —    | ns    |
| t <sub>AWD</sub>  | Column-Address to $\overline{\text{WE}}$ Delay Time <sup>(14)</sup>                                            | 30   | —    | 30   | —    | 49   | —    | ns    |
| t <sub>PC</sub>   | EDO Page Mode READ or WRITE Cycle Time <sup>(24)</sup>                                                         | 12   | —    | 15   | —    | 25   | —    | ns    |
| t <sub>RASP</sub> | $\overline{\text{RAS}}$ Pulse Width in EDO Page Mode                                                           | 35   | 100K | 40   | 100K | 50   | 100K | ns    |
| t <sub>CPA</sub>  | Access Time from $\overline{\text{CAS}}$ Precharge <sup>(15)</sup>                                             | —    | 21   | —    | 27   | —    | 34   | ns    |
| t <sub>PRWC</sub> | EDO Page Mode READ-WRITE Cycle Time <sup>(24)</sup>                                                            | 40   | —    | 45   | —    | 56   | —    | ns    |
| t <sub>COH</sub>  | Data Output Hold after $\overline{\text{CAS}}$ LOW                                                             | 5    | —    | 5    | —    | 5    | —    | ns    |
| t <sub>OFF</sub>  | Output Buffer Turn-Off Delay from $\overline{\text{CAS}}$ or $\overline{\text{RAS}}$ <sup>(13,15,19, 29)</sup> | 3    | 15   | 3    | 15   | 3    | 15   | ns    |
| t <sub>WHZ</sub>  | Output Disable Delay from $\overline{\text{WE}}$                                                               | 3    | 15   | 3    | 15   | 3    | 15   | ns    |
| t <sub>CLCH</sub> | Last $\overline{\text{CAS}}$ going LOW to First $\overline{\text{CAS}}$ returning HIGH <sup>(23)</sup>         | 10   | —    | 10   | —    | 10   | —    | ns    |
| t <sub>CSR</sub>  | $\overline{\text{CAS}}$ Setup Time (CBR REFRESH) <sup>(30, 20)</sup>                                           | 8    | —    | 10   | —    | 10   | —    | ns    |
| t <sub>CHR</sub>  | $\overline{\text{CAS}}$ Hold Time (CBR REFRESH) <sup>(30, 21)</sup>                                            | 8    | —    | 10   | —    | 10   | —    | ns    |
| t <sub>ORD</sub>  | $\overline{\text{OE}}$ Setup Time prior to $\overline{\text{RAS}}$ during HIDDEN REFRESH Cycle                 | 0    | —    | 0    | —    | 0    | —    | ns    |
| t <sub>REF</sub>  | Refresh Period (1024 Cycles)                                                                                   | —    | 16   | 16   | —    | 16   | —    | ms    |
| t <sub>r</sub>    | Transition Time (Rise or Fall) <sup>(2, 3)</sup>                                                               | 1    | 50   | 1    | 50   | 1    | 50   | ns    |

Notes:

1. An initial pause of 200  $\mu$ s is required after power-up followed by eight  $\overline{\text{RAS}}$  refresh cycle ( $\overline{\text{RAS}}$ -Only or CBR) before proper device operation is assured. The eight  $\overline{\text{RAS}}$  cycles wake-up should be repeated any time the  $t_{\text{REF}}$  refresh requirement is exceeded.
2.  $V_{\text{IH}}$  (MIN) and  $V_{\text{IL}}$  (MAX) are reference levels for measuring timing of input signals. Transition times, are measured between  $V_{\text{IH}}$  and  $V_{\text{IL}}$  (or between  $V_{\text{IL}}$  and  $V_{\text{IH}}$ ) and assume to be 1 ns for all inputs.
3. In addition to meeting the transition rate specification, all input signals must transit between  $V_{\text{IH}}$  and  $V_{\text{IL}}$  (or between  $V_{\text{IL}}$  and  $V_{\text{IH}}$ ) in a monotonic manner.
4. If  $\overline{\text{CAS}}$  and  $\overline{\text{RAS}} = V_{\text{IH}}$ , data output is High-Z.
5. If  $\overline{\text{CAS}} = V_{\text{IL}}$ , data output may contain data from the last valid READ cycle.
6. Measured with a load equivalent to one TTL gate and 50 pF.
7. Assumes that  $t_{\text{RCD}} \leq t_{\text{RCD}} (\text{MAX})$ . If  $t_{\text{RCD}}$  is greater than the maximum recommended value shown in this table,  $t_{\text{RAC}}$  will increase by the amount that  $t_{\text{RCD}}$  exceeds the value shown.
8. Assumes that  $t_{\text{RCD}} \geq t_{\text{RCD}} (\text{MAX})$ .
9. If  $\overline{\text{CAS}}$  is LOW at the falling edge of  $\overline{\text{RAS}}$ , data out will be maintained from the previous cycle. To initiate a new cycle and clear the data output buffer,  $\overline{\text{CAS}}$  and  $\overline{\text{RAS}}$  must be pulsed for  $t_{\text{CP}}$ .
10. Operation with the  $t_{\text{RCD}} (\text{MAX})$  limit ensures that  $t_{\text{RAC}} (\text{MAX})$  can be met.  $t_{\text{RCD}} (\text{MAX})$  is specified as a reference point only; if  $t_{\text{RCD}}$  is greater than the specified  $t_{\text{RCD}} (\text{MAX})$  limit, access time is controlled exclusively by  $t_{\text{CAC}}$ .
11. Operation within the  $t_{\text{RAD}} (\text{MAX})$  limit ensures that  $t_{\text{RCD}} (\text{MAX})$  can be met.  $t_{\text{RAD}} (\text{MAX})$  is specified as a reference point only; if  $t_{\text{RAD}}$  is greater than the specified  $t_{\text{RAD}} (\text{MAX})$  limit, access time is controlled exclusively by  $t_{\text{AA}}$ .
12. Either  $t_{\text{RCH}}$  or  $t_{\text{RRH}}$  must be satisfied for a READ cycle.
13.  $t_{\text{OFF}} (\text{MAX})$  defines the time at which the output achieves the open circuit condition; it is not a reference to  $V_{\text{OH}}$  or  $V_{\text{OL}}$ .
14.  $t_{\text{WCS}}$ ,  $t_{\text{RWD}}$ ,  $t_{\text{AWD}}$  and  $t_{\text{CWD}}$  are restrictive operating parameters in LATE WRITE and READ-MODIFY-WRITE cycle only. If  $t_{\text{WCS}} \geq t_{\text{WCS}} (\text{MIN})$ , the cycle is an EARLY WRITE cycle and the data output will remain open circuit throughout the entire cycle. If  $t_{\text{RWD}} \geq t_{\text{RWD}} (\text{MIN})$ ,  $t_{\text{AWD}} \geq t_{\text{AWD}} (\text{MIN})$  and  $t_{\text{CWD}} \geq t_{\text{CWD}} (\text{MIN})$ , the cycle is a READ-WRITE cycle and the data output will contain data read from the selected cell. If neither of the above conditions is met, the state of I/O (at access time and until  $\overline{\text{CAS}}$  and  $\overline{\text{RAS}}$  or  $\overline{\text{OE}}$  go back to  $V_{\text{IH}}$ ) is indeterminate.  $\overline{\text{OE}}$  held HIGH and  $\overline{\text{WE}}$  taken LOW after  $\overline{\text{CAS}}$  goes LOW result in a LATE WRITE ( $\overline{\text{OE}}$ -controlled) cycle.
15. Output parameter (I/O) is referenced to corresponding  $\overline{\text{CAS}}$  input.
16. During a READ cycle, if  $\overline{\text{OE}}$  is LOW then taken HIGH before  $\overline{\text{CAS}}$  goes HIGH, I/O goes open. If  $\overline{\text{OE}}$  is tied permanently LOW, a LATE WRITE or READ-MODIFY-WRITE is not possible.
17. Write command is defined as  $\overline{\text{WE}}$  going low.
18. LATE WRITE and READ-MODIFY-WRITE cycles must have both  $t_{\text{OD}}$  and  $t_{\text{OEH}}$  met ( $\overline{\text{OE}}$  HIGH during WRITE cycle) in order to ensure that the output buffers will be open during the WRITE cycle. The I/Os will provide the previously written data if  $\overline{\text{CAS}}$  remains LOW and  $\overline{\text{OE}}$  is taken back to LOW after  $t_{\text{OEH}}$  is met.
19. The I/Os are in open during READ cycles once  $t_{\text{OD}}$  or  $t_{\text{OFF}}$  occur.
20. The first  $\chi\overline{\text{CAS}}$  edge to transition LOW.
21. The last  $\chi\overline{\text{CAS}}$  edge to transition HIGH.
22. These parameters are referenced to  $\overline{\text{CAS}}$  leading edge in EARLY WRITE cycles and  $\overline{\text{WE}}$  leading edge in LATE WRITE or READ-MODIFY-WRITE cycles.
23. Last falling  $\chi\overline{\text{CAS}}$  edge to first rising  $\chi\overline{\text{CAS}}$  edge.
24. Last rising  $\chi\overline{\text{CAS}}$  edge to next cycle's last rising  $\chi\overline{\text{CAS}}$  edge.
25. Last rising  $\chi\overline{\text{CAS}}$  edge to first falling  $\chi\overline{\text{CAS}}$  edge.
26. Each  $\chi\overline{\text{CAS}}$  must meet minimum pulse width.
27. Last  $\chi\overline{\text{CAS}}$  to go LOW.
28. I/Os controlled, regardless  $\overline{\text{CAS}}$ .
29. The 3 ns minimum is a parameter guaranteed by design.
30. Enables on-chip refresh and address counters.

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The diagram illustrates the timing relationships for a 2D array memory device. The signals and their timing parameters are as follows:

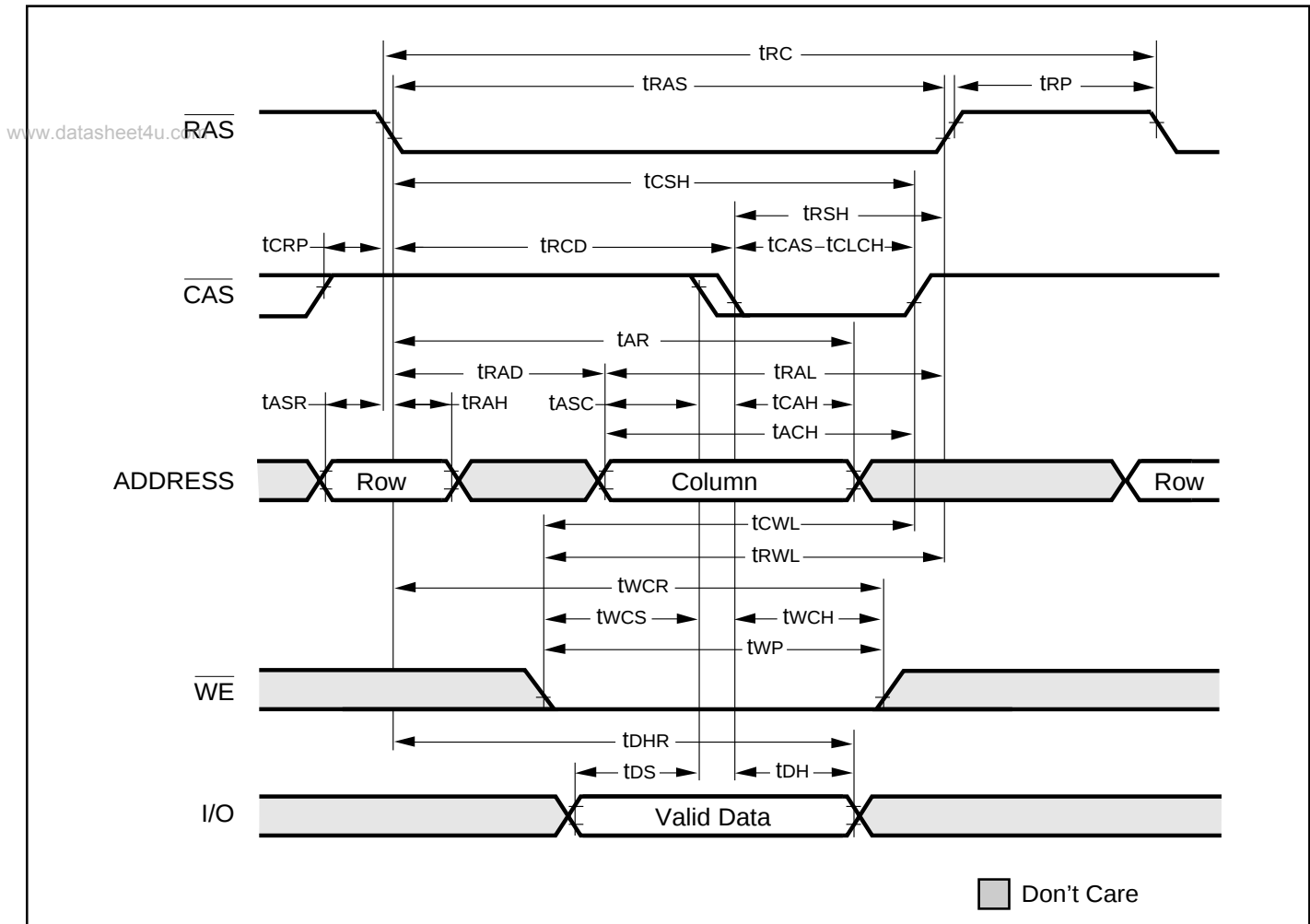
- RAS**: Row Address Strobe. Timing parameters include  $t_{RC}$  (RAS to next RAS),  $t_{RAS}$  (RAS pulse width),  $t_{TRP}$  (RAS to next RAS),  $t_{CRP}$  (RAS to next CAS),  $t_{CSDH}$  (RAS to next CAS),  $t_{RRH}$  (RAS to next RAS),  $t_{RSH}$  (RAS to next RAS), and  $t_{RCH}$  (RAS to next RAS).
- CAS**: Column Address Strobe. Timing parameters include  $t_{CD}$  (CAS to next CAS),  $t_{CAS}$  (CAS pulse width),  $t_{CLCH}$  (CAS to next CAS),  $t_{CRP}$  (RAS to next CAS),  $t_{CSDH}$  (RAS to next CAS),  $t_{RRH}$  (RAS to next RAS),  $t_{RSH}$  (RAS to next RAS), and  $t_{RCH}$  (RAS to next RAS).
- ADDRESS**: Row and Column addresses. Timing parameters include  $t_{ASR}$  (Address to next Address),  $t_{RAH}$  (Row Address to next Row Address),  $t_{ASC}$  (Column Address to next Column Address),  $t_{CAH}$  (Row Address to next Row Address),  $t_{RCS}$  (Row Address to next Row Address), and  $t_{RCH}$  (Row Address to next Row Address).
- WE**: Write Enable. Timing parameters include  $t_{TAA}$  (Write Enable to next Write Enable),  $t_{TAC}$  (Write Enable to next Write Enable),  $t_{CAC}$  (Write Enable to next Write Enable),  $t_{CLC}$  (Write Enable to next Write Enable),  $t_{TOE}$  (Write Enable to next Write Enable), and  $t_{TOD}$  (Write Enable to next Write Enable).
- I/O**: Data bus. Timing parameters include  $t_{OE}$  (Output Enable to next Output Enable),  $t_{OD}$  (Output Disable to next Output Disable),  $t_{TOE}$  (Output Enable to next Output Enable), and  $t_{TOD}$  (Output Disable to next Output Disable).
- OE**: Output Enable. Timing parameters include  $t_{OE}$  (Output Enable to next Output Enable),  $t_{OD}$  (Output Disable to next Output Disable),  $t_{TOE}$  (Output Enable to next Output Enable), and  $t_{TOD}$  (Output Disable to next Output Disable).

Legend:

- Undefined (Cross-hatched box)
- Don't Care (Gray box)

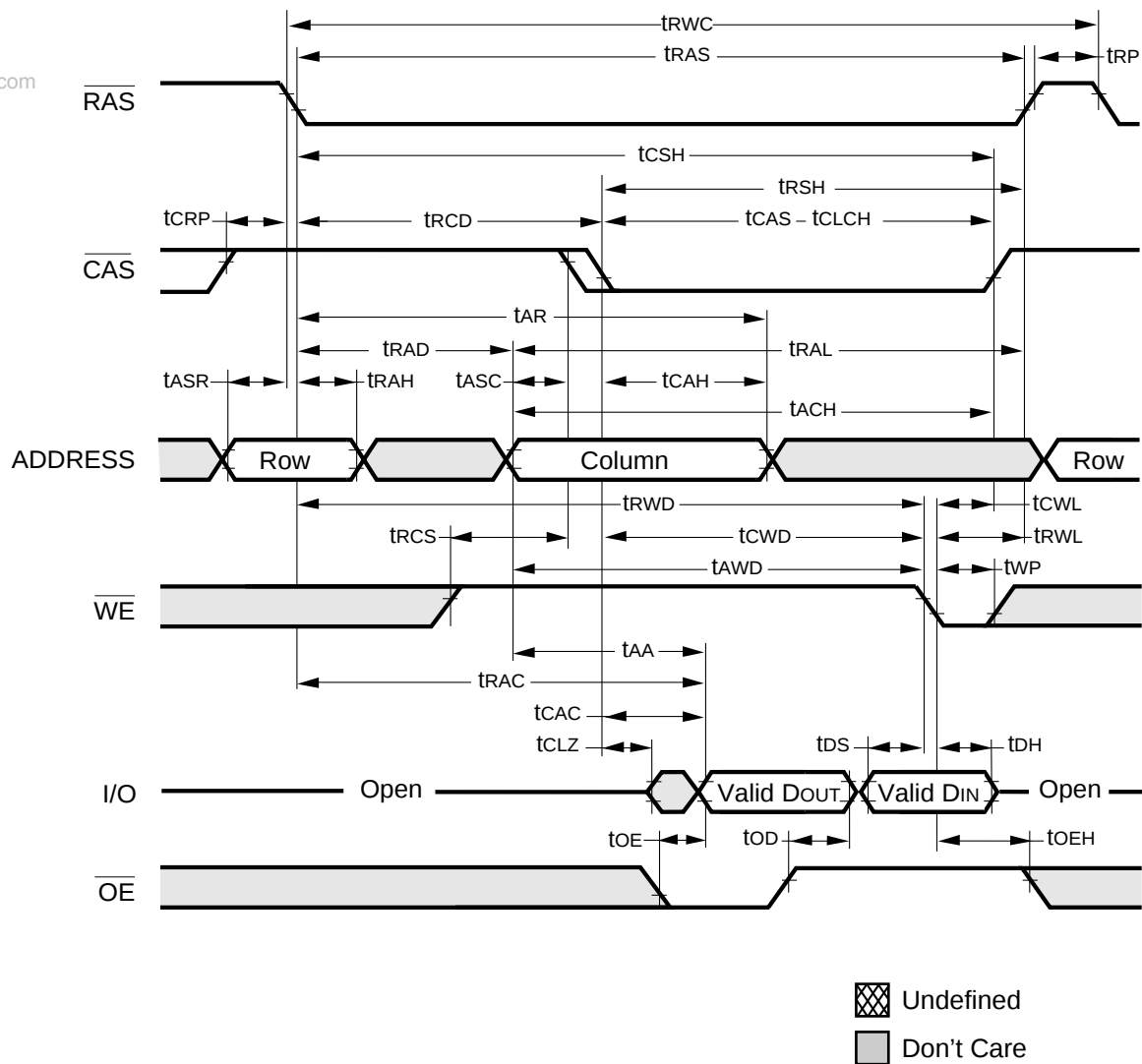
1.  $t_{OFF}$  is referenced from rising edge of  $\overline{RAS}$  or  $\overline{CAS}$ , whichever occurs last.

EARLY WRITE CYCLE ( $\overline{OE}$  = DON'T CARE)



READ WRITE CYCLE (LATE WRITE and READ-MODIFY-WRITE Cycles)

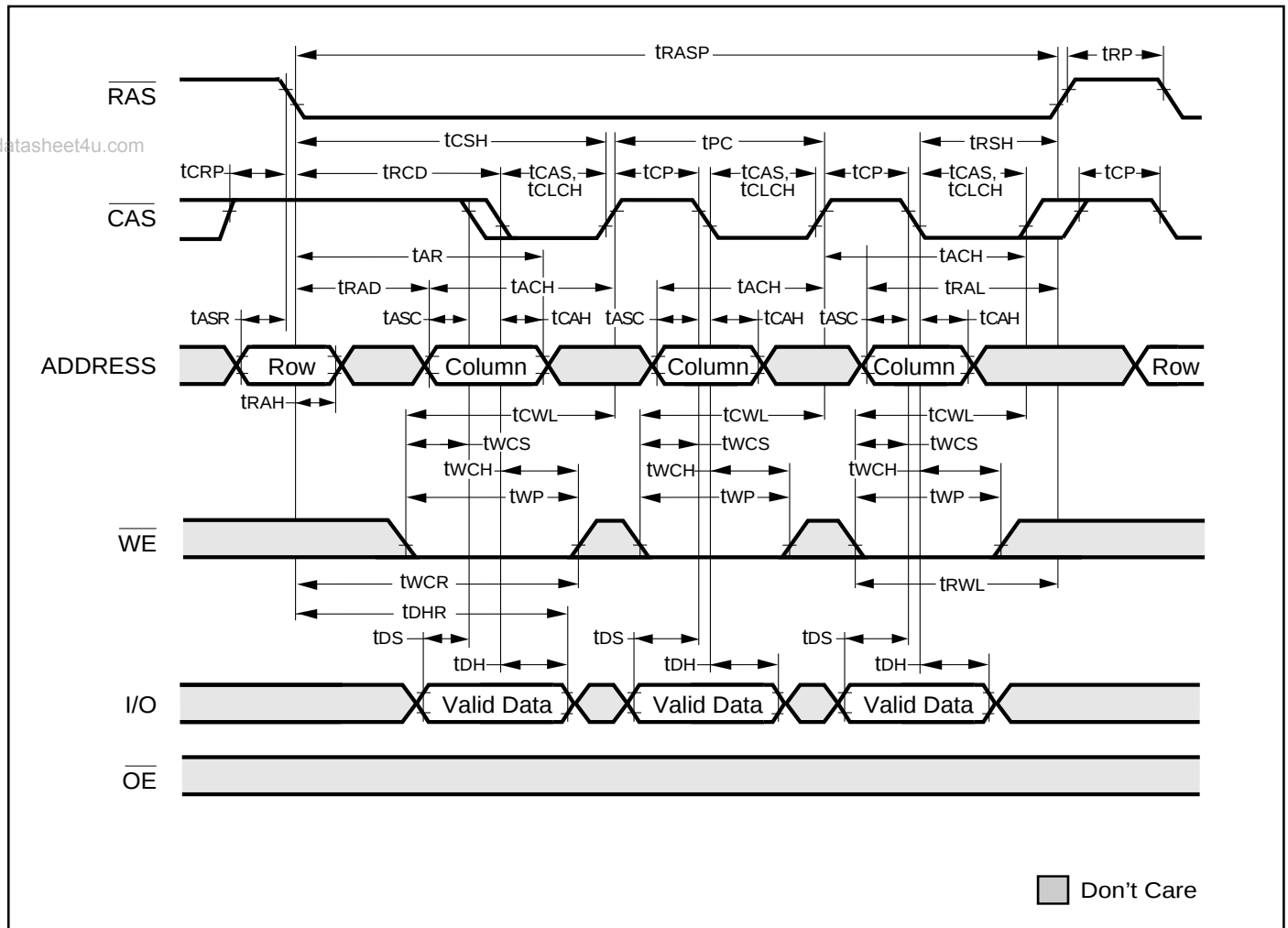
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## EDO-PAGE-MODE EARLY-WRITE CYCLE



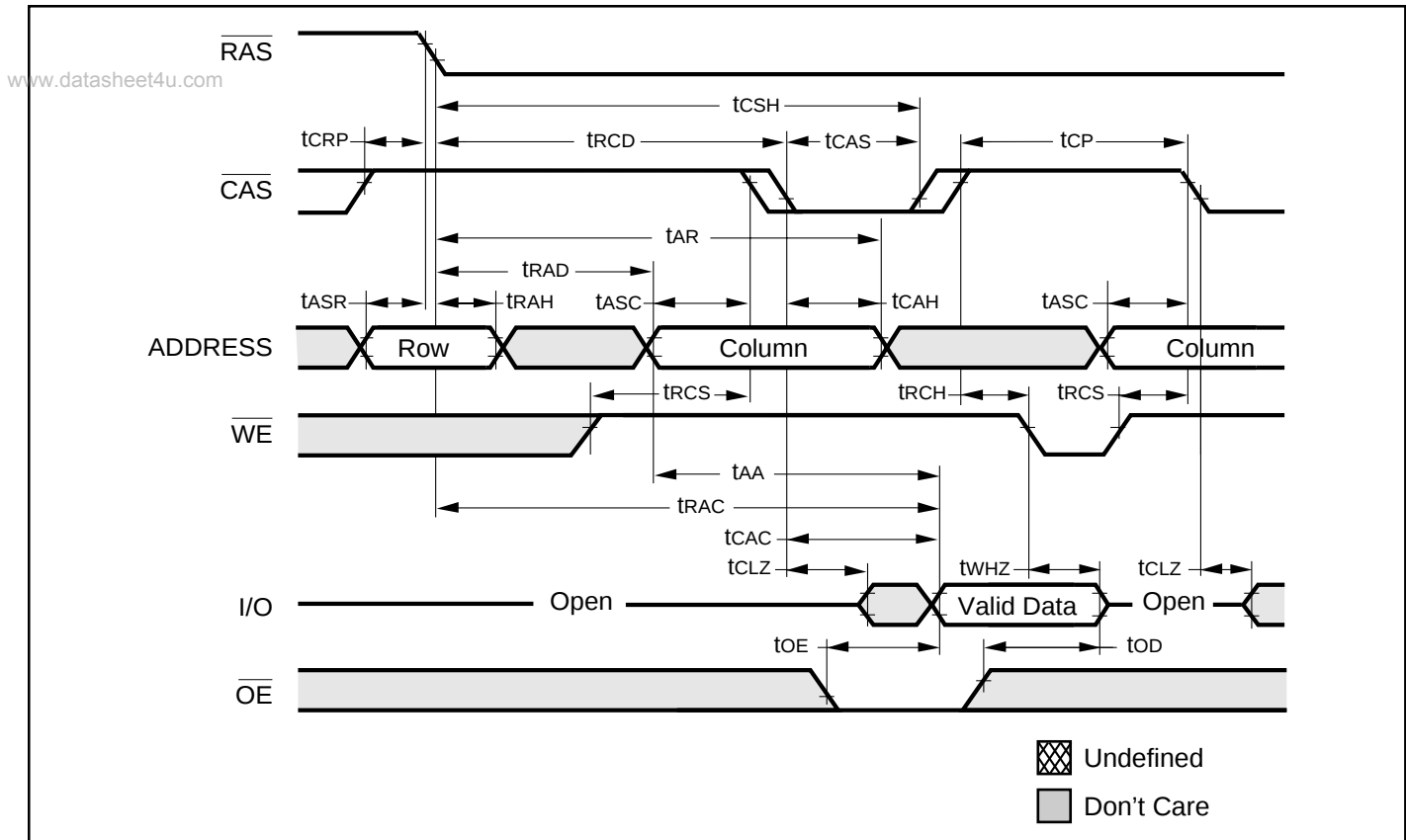
Timing diagram for the 64Kbit 16M16000 SDRAM. The diagram illustrates the relationship between RAS, CAS, ADDRESS, WE, I/O, and OE signals over time. Key timing parameters are labeled, including  $t_{RASP}$ ,  $t_{RSH}$ ,  $t_{RCD}$ ,  $t_{CAS}$ ,  $t_{CLCH}$ ,  $t_{CP}$ ,  $t_{PC}$ ,  $t_{PRWC}^{(1)}$ ,  $t_{AR}$ ,  $t_{ASR}$ ,  $t_{AD}$ ,  $t_{CAH}$ ,  $t_{ASC}$ ,  $t_{AL}$ ,  $t_{RWD}$ ,  $t_{RCS}$ ,  $t_{CWL}$ ,  $t_{WP}$ ,  $t_{AWD}$ ,  $t_{CWD}$ ,  $t_{AA}$ ,  $t_{ACPA}$ ,  $t_{DH}$ ,  $t_{DS}$ ,  $t_{CAC}$ ,  $t_{CLZ}$ ,  $t_{OE}$ ,  $t_{OD}$ , and  $t_{OEH}$ . The ADDRESS signal is shown with Row and Column address periods. The I/O signal shows data output (DOUT) and data input (DIN) periods. The OE signal is shown as an output enable signal. A legend indicates that cross-hatched areas are 'Undefined' and solid grey areas are 'Don't Care'.

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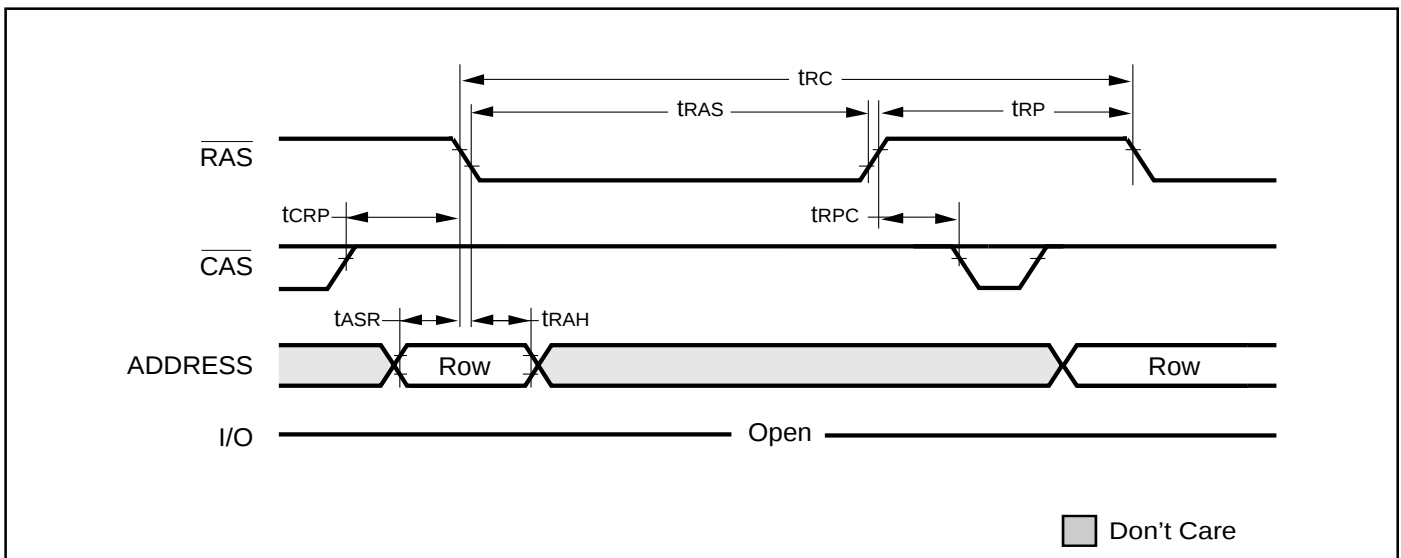
The diagram illustrates the timing relationships for a 2D DRAM array. The signals shown are  $\overline{\text{RAS}}$ ,  $\overline{\text{CAS}}$ , ADDRESS,  $\overline{\text{WE}}$ , I/O, and  $\overline{\text{OE}}$ . The ADDRESS signal is divided into Row and Column (A, B, N) segments. The I/O signal shows Valid Data (A) and Valid Data (B) periods, with a DIN signal during the second valid data period. The  $\overline{\text{OE}}$  signal is active low. Various timing parameters are indicated by arrows, such as  $t_{\text{RASP}}$  (RAS pulse width),  $t_{\text{CRP}}$  (CAS-to-RAS precharge),  $t_{\text{RCD}}$  (RAS-to-CAS delay),  $t_{\text{CAS}}$  (CAS pulse width),  $t_{\text{PC}}$  (RAS-to-CAS precharge),  $t_{\text{TRSH}}$  (RAS-to-CAS precharge),  $t_{\text{TAR}}$  (RAS-to-Address delay),  $t_{\text{ASR}}$  (Address-to-RAS delay),  $t_{\text{TRAH}}$  (Address-to-RAS delay),  $t_{\text{ASC}}$  (Address-to-CAS delay),  $t_{\text{CAH}}$  (Address-to-CAS delay),  $t_{\text{RCS}}$  (RAS-to-CAS delay),  $t_{\text{RCH}}$  (RAS-to-CAS delay),  $t_{\text{TAA}}$  (RAS-to-Address delay),  $t_{\text{TRAC}}$  (RAS-to-Address delay),  $t_{\text{CAC}}$  (CAS-to-Address delay),  $t_{\text{CPA}}$  (CAS-to-Address delay),  $t_{\text{COH}}$  (CAS-to-Address delay),  $t_{\text{DPS}}$  (Data-to-Address delay),  $t_{\text{DTH}}$  (Data-to-Address delay),  $t_{\text{OE}}$  (Output Enable delay),  $t_{\text{WHZ}}$  (Write Hold time),  $t_{\text{WCS}}$  (Write-to-CAS delay), and  $t_{\text{WCH}}$  (Write-to-CAS delay). A legend indicates that a gray box represents 'Don't Care'.

## AC WAVEFORMS

### READ CYCLE (With $\overline{WE}$ -Controlled Disable)



### $\overline{RAS}$ -ONLY REFRESH CYCLE ( $\overline{OE}$ , $\overline{WE}$ = DON'T CARE)



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## ORDERING INFORMATION

### IS41C8512

Commercial Range: 0°C to 70°C

| Speed (ns) | Order Part No. | Package       |
|------------|----------------|---------------|
| 35         | IS41C8512-35K  | 400mil SOJ    |
|            | IS41C8512-35T  | 400mil TSOP-2 |
| 50         | IS41C8512-50K  | 400mil SOJ    |
|            | IS41C8512-50T  | 400mil TSOP-2 |
| 60         | IS41C8512-60K  | 400mil SOJ    |
|            | IS41C8512-60T  | 400mil TSOP-2 |

## ORDERING INFORMATION:

### IS41LV8512

Commercial Range: 0°C to 70°C

| Speed (ns) | Order Part No. | Package       |
|------------|----------------|---------------|
| 35         | IS41LV8512-35K | 400mil SOJ    |
|            | IS41LV8512-35T | 400mil TSOP-2 |
| 50         | IS41LV8512-50K | 400mil SOJ    |
|            | IS41LV8512-50T | 400mil TSOP-2 |
| 60         | IS41LV8512-60K | 400mil SOJ    |
|            | IS41LV8512-60T | 400mil TSOP-2 |

Industrial Range: -40°C to 85°C

| Speed (ns) | Order Part No. | Package       |
|------------|----------------|---------------|
| 35         | IS41C8512-35KI | 400mil SOJ    |
|            | IS41C8512-35TI | 400mil TSOP-2 |
| 50         | IS41C8512-50KI | 400mil SOJ    |
|            | IS41C8512-50TI | 400mil TSOP-2 |
| 60         | IS41C8512-60KI | 400mil SOJ    |
|            | IS41C8512-60TI | 400mil TSOP-2 |

Industrial Range: -40°C to 85°C

| Speed (ns) | Order Part No.  | Package       |
|------------|-----------------|---------------|
| 35         | IS41LV8512-35K  | 400mil SOJ    |
|            | IS41LV8512-35T  | 400mil TSOP-2 |
| 50         | IS41LV8512-50KI | 400mil SOJ    |
|            | IS41LV8512-50TI | 400mil TSOP-2 |
| 60         | IS41LV8512-60KI | 400mil SOJ    |
|            | IS41LV8512-60TI | 400mil TSOP-2 |



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